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CLAIMS

What is claimed is:

5	1.	a measuring system of a gas-stream environment, s	aid
	measuring system comprises:		

a stage, wherein said stage is located on a transport apparatus and used to place a wafer;

a datum platen, wherein said datum platen is located on said transport apparatus and on a side of said stage to be used to place a datum slice;

a lens, wherein said lens is located above said stage to measure said wafer and said datum slice;

a gas supplier, wherein said gas supplier is used to supply a gas;

a first gas nozzle, wherein said first gas nozzle is located on a side of said datum platen and is used to exhaust said gas;

a second gas nozzle, wherein said second gas nozzle is located on a side of said stage and is used to exhaust said gas;

a first tube, wherein said first tube is connected with said first gas nozzle and said gas supplier;

a second tube, wherein said second tube is connected with said second gas nozzle and said gas supplier;

a transport slot, wherein said transport slot is an opening to exhaust said gas; and

a gas-extracting apparatus, wherein said gas-extracting apparatus connects with said transport slot by using a third tube and is used to produce a attraction to remove said gas.

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- 2. The system according to claim 1, wherein said first tube comprises a flow rate regulating valve.
- The system according to claim 1, wherein said secondtube comprises a flow rate regulating valve.
 - 4. The system according to claim 1, wherein said gasextracting apparatus comprises a gas-extracting motor.
- 10 5. The system according to claim 1, wherein said gasextracting apparatus comprises a venturi structure.
 - 6. The system according to claim 1, wherein said gas is a inert gas.

7. The system according to claim 1, wherein said gas is a nitrogen.

- 8. The system according to claim 1, wherein said gas supplier comprises a flow rate regulating valve.
 - 9. a measuring system of a gas-stream environment, said measuring system comprises:

a stage, wherein said stage is located on a transport apparatus and used to place a wafer;

a datum platen, wherein said datum platen is located on said transport apparatus and on a side of said stage to be used to place a datum slice;

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a lens,	wherein said lens is	s located above	said stage	e to measure
said wafer and	said datum slice;			

a gas supplier, wherein said gas supplier is used to supply a gas;

a first gas nozzle, wherein said first gas nozzle is located on a side of said datum platen to exhaust said gas and comprises a first flow rate regulating valve;

a second gas nozzle, wherein said second gas nozzle is located on a side of said stage to exhaust said gas and comprises a first flow rate regulating valve;

a first tube, wherein said first tube is connected with said first gas nozzle and said gas supplier;

a second tube, wherein said second tube is connected with said second gas nozzle and said gas supplier;

a transport slot, wherein said transport slot is an opening to exhaust said gas; and

a gas-extracting apparatus, wherein said gas-extracting apparatus connects with said transport slot by using a third tube and is used to produce a attraction to remove said gas.

- 20 10. The system according to claim 9, wherein said first tube comprises a flow rate regulating valve.
 - 11. The system according to claim 9, wherein said second tube comprises a flow rate regulating valve.
 - 12. The system according to claim 9, wherein said gasextracting apparatus comprises a gas-extracting motor.

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- 13. The system according to claim 9, wherein said gasextracting apparatus comprises a venturi structure.
- 14. The system according to claim 9, wherein said gas is a5 inert gas.
 - 15. The system according to claim 9, wherein said gas is a nitrogen.
- 10 16. The system according to claim 9, wherein said gas supplier comprises a flow rate regulating valve.
 - 17. a measuring system of a gas-stream environment, said measuring system comprises:

a stage, wherein said stage is located on a transport apparatus and used to place a wafer;

a datum platen, wherein said datum platen is located on said transport apparatus and on a side of said stage to be used to place a datum slice;

a lens, wherein said lens is located above said stage to measure said wafer and said datum slice;

a gas supplier, wherein said gas supplier is used to supply a gas; a first gas nozzle, wherein said first gas nozzle is located on a side of said datum platen and on said transport apparatus to exhaust said gas;

a second gas nozzle, wherein said second gas nozzle is located on a side of said stage and on said transport apparatus to exhaust said gas;

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a first tube, wherein said first tube comprises a first flow rate regulating valve and is connected with said first gas nozzle and said gas supplier;

a second tube, wherein said second tube comprises a second flow rate regulating valve and is connected with said second gas nozzle and said gas supplier;

a transport slot, wherein said transport slot is an opening to exhaust said gas; and

- a gas-extracting apparatus, wherein said gas-extracting apparatus connects with said transport slot by using a third tube and is used to produce a attraction to remove said gas.
 - 18. The system according to claim 17, wherein said gasextracting apparatus comprises a venturi structure.
 - 19. The system according to claim 17, wherein said gas is a inert gas.
- The system according to claim 17, wherein said gas is a nitrogen.